

1	<b>SCANNING OR POSITIONING ARRANGEMENTS, I.E., ARRANGEMENTS FOR ACTIVELY CONTROLLING THE MOVEMENT OR POSITION OF THE PROBE</b>	23	..Scanning Tunnelling Microscopy [STM] combined with Atomic Force Microscopy [AFM]
2	.Coarse scanning or positioning		
3	.Fine scanning or positioning		
4	..Circuits or algorithms therefor	24	..Scanning Near-field Optical Microscopy [SNOM] combined with Atomic Force Microscopy [AFM]
5	<b>MONITORING THE MOVEMENT OR POSITION OF THE PROBE RESPONSIVE TO INTERACTION WITH THE SAMPLE</b>	25	..Magnetic Force Microscopy [MFM] combined with Atomic Force Microscopy [AFM]
6	.By optical means	26	.Scanning Tunnelling Microscopy [STM] or apparatus therefor, e.g., STM probes
7	.Self-detecting probes	27	..Scanning Tunnelling Spectroscopy [STS]
8	<b>AUXILIARY MEANS SERVING TO ASSIST OR IMPROVE THE SCANNING PROBE TECHNIQUES OR APPARATUS, E.G., DISPLAY OR DATA PROCESSING DEVICES</b>	28	..Scanning tunnelling potentiometry [STP]
9	.Non-SPM analyzing devices, e.g., Scanning Electron Microscope [SEM], spectrometer or optical microscope	29	..Probes, their manufacture, or their related instrumentation, e.g., holders
10	.Display or data processing devices	30	.Scanning Near-Field Optical Microscopy [SNOM] or apparatus therefor, e.g., SNOM probes
11	..For error compensation	31	..Fluorescence
12	.Means for establishing or regulating a desired environmental condition within a sample chamber	32	..Probes, their manufacture, or their related instrumentation, e.g., holders
13	..Thermal environment	33	.Atomic Force Microscopy [AFM] or apparatus therefor, e.g., AFM probes
14	..Fluid environment	34	..Friction force microscopy
15	...Liquid environment	35	..Adhesion force microscopy
16	..Vacuum environment	36	..Scanning potential microscopy
17	.Means for protecting or isolating the interior of a sample chamber from external environmental conditions or influences, e.g., vibrations or electromagnetic fields	37	..AC mode
18	.Sample handling device or method	38	...Tapping mode
19	<b>CALIBRATION ASPECT, E.G., CALIBRATION OF PROBES</b>	39	..DC mode
20	.Calibration standards and methods of fabrication thereof	40	..Probes, their manufacture, or their related instrumentation, e.g., holders
21	<b>PARTICULAR TYPE OF SCANNING PROBE MICROSCOPY [SPM] OR MICROSCOPE; ESSENTIAL COMPONENTS THEREOF</b>	41	...Conductive probes
22	.Multiple-type SPM, i.e., involving two or more SPM techniques	42	...Functionalization
		43	.Scanning Ion-Conductance Microscopy [SICM] or apparatus therefor, e.g., SICM probes
		44	.Scanning Capacitance Microscopy [SCM] or apparatus therefor, e.g., SCM probes
		45	..Probes, their manufacture, or their instrumentation, e.g., holders
		46	.Magnetic Force Microscopy [MFM] or apparatus therefor, e.g., MFM probes
		47	..Resonance

- 48 ..Probes, their manufacture, or  
their related instrumentation,  
e.g., holders
- 49 ...Probes with magnetic coating
- 50 .Scanning Thermal Microscopy  
[SThM] or apparatus therefor,  
e.g., SThM probes
- 51 .Scanning Electro-Chemical  
Microscopy [SECM] or apparatus  
therefor, e.g., SECM probes
- 52 **GENERAL ASPECTS OF SPM PROBES,  
THEIR MANUFACTURE, OR THEIR  
RELATED INSTRUMENTATION,  
INSOFAR AS THEY ARE NOT  
SPECIALLY ADAPTED TO A SINGLE  
SPECIFIC SPM TECHNIQUE**
- 53 .Probe holders
- 54 ..With compensation for  
temperature or vibration  
induced errors
- 55 .Probe tip arrays
- 56 .Probe characteristics
- 57 ..Shape or taper
- 58 ..Nano-tube tips
- 59 ..Particular materials
- 60 .Probe manufacture
- 61 ..Functionalization
- 62 **APPLICATIONS OF SCANNING-PROBE  
TECHNIQUES OTHER THAN SPM**
- 63 **SCANNING-PROBE TECHNIQUES OR  
APPARATUS NOT OTHERWISE  
PROVIDED FOR**